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Fairchild Semiconductor FDPF5N50T

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# FAIRCHILD

SEMICONDUCTOR®

## **FDPF5N50T** N-Channel UniFET<sup>TM</sup> MOSFET 500 V, 5 A, 1.4 Ω

## Features

- +  $R_{DS(on)}$  = 1.15  $\Omega$  (Typ.) @  $V_{GS}$  = 10 V,  $I_D$  = 2.5 A
- Low Gate Charge (Typ. 11 nC)
- Low C<sub>rss</sub> (Typ. 5 pF)
- 100% Avalanche Tested
- Improved dv/dt Capability
- RoHS Compliant

## **Applications**

- LCD/LED TV
- Lighting
- Uninterruptible Power Supply
- AC-DC Power Supplylications

## Description

UniFET<sup>TM</sup> MOSFET is Fairchild Semiconductor's high voltage MOSFET family based on planar stripe and DMOS technology. This MOSFET is tailored to reduce on-state resistance, and to provide better switching performance and higher avalanche energy strength. This device family is suitable for switching power converter applications such as power factor correction (PFC), flat panel display (FPD) TV power, ATX and electronic lamp ballasts.



# GO

## Absolute Maximum Ratings T<sub>C</sub> = 25°C unless otherwise noted.

Drain to Source Voltage Gate to Source Voltage			500	-
Gate to Source Voltage			500	V
			±30	V
Dania Quanant	- Continuous (T <sub>C</sub> = 25 <sup>o</sup> C)		5*	
Drain Current	- Continuous (T <sub>C</sub> = 100 <sup>o</sup> C)		3*	Α
Drain Current	- Pulsed	(Note 1)	20*	Α
Single Pulsed Avalanche E	inergy	(Note 2)	225	mJ
Avalanche Current		(Note 1)	5	A
Repetitive Avalanche Ener	ду	(Note 1)	8.5	mJ
Peak Diode Recovery dv/d	t	(Note 3)	4.5	V/ns
Dower Dissinction	(T <sub>C</sub> = 25°C)		28	W
P <sub>D</sub> Power Dissipation	- Derate Above 25°C		0.22	W/ºC
Operating and Storage Temperature Range		-55 to +150	°C	
Maximum Lead Temperature for Soldering, 1/8" from Case for 5 Seconds			300	٥C
	Single Pulsed Avalanche E Avalanche Current Repetitive Avalanche Ener Peak Diode Recovery dv/d Power Dissipation Operating and Storage Ter Maximum Lead Temperatu	Drain Current       - Continuous ( $T_c = 100^{\circ}C$ )         Drain Current       - Pulsed         Single Pulsed Avalanche Energy         Avalanche Current         Repetitive Avalanche Energy         Peak Diode Recovery dv/dt         Power Dissipation         ( $T_c = 25^{\circ}C$ )         - Derate Above 25^{\circ}C         Operating and Storage Temperature Range	Drain Current       - Continuous ( $T_c = 100^{\circ}C$ )         Drain Current       - Pulsed       (Note 1)         Single Pulsed Avalanche Energy       (Note 2)         Avalanche Current       (Note 1)         Repetitive Avalanche Energy       (Note 1)         Peak Diode Recovery dv/dt       (Note 3)         Power Dissipation $(T_c = 25^{\circ}C)$ Operating and Storage Temperature Range       Odering, 1/8" from Case for 5 Seconds	Drain Current- Continuous ( $T_c = 100^{\circ}C$ ) $3^*$ Drain Current- Pulsed(Note 1) $20^*$ Single Pulsed Avalanche Energy(Note 2) $225$ Avalanche Current(Note 1)5Repetitive Avalanche Energy(Note 1)8.5Peak Diode Recovery dv/dt(Note 3)4.5Power Dissipation( $T_c = 25^{\circ}C$ )28- Derate Above $25^{\circ}C$ 0.22Operating and Storage Temperature Range-55 to +150Maximum Lead Temperature for Soldering, 1/8" from Case for 5 Seconds300

## **Thermal Characteristics**

Symbol	Parameter	FDPF5N50T	Unit	
$R_{ extsf{ heta}JC}$	Thermal Resistance, Junction to Case, Max.	4.5	°C/W	
$R_{ extsf{ heta}JA}$	Thermal Resistance, Junction to Ambient, Max.	62.5	°C/W	

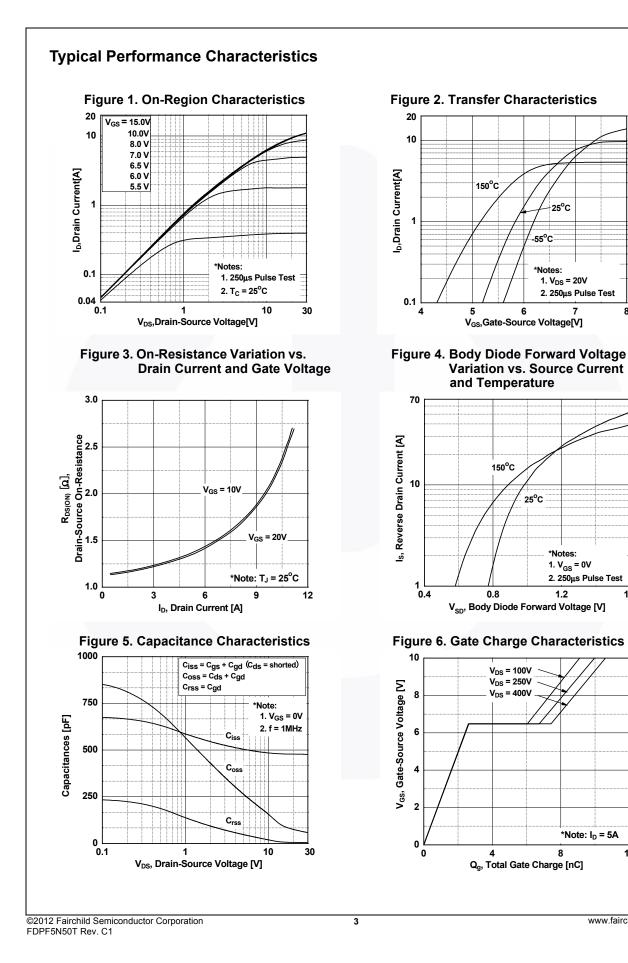
November 2013



acteristics       T <sub>C</sub> = 25°C unit         Parameter       S         o Source Breakdown Voltage       S         own Voltage Temperature       S         ate Voltage Drain Current       Body Leakage Current	Test Conditi $I_D$ = 250 μA, $V_{GS}$ = 0 V $I_D$ = 250 μA, Reference $V_{DS}$ = 500 V, $V_{GS}$ = 0 V $V_{DS}$ = 400 V, $T_C$ = 125	/, $T_J = 25^{\circ}C$ ed to $25^{\circ}C$ V	Min. 500 -	<b>Typ.</b>	Max. - -	Unit V V/ºC
<b>S</b> Source Breakdown Voltage own Voltage Temperature ent ate Voltage Drain Current	$I_{D} = 250 \ \mu\text{A}, \ V_{GS} = 0 \ V$ $I_{D} = 250 \ \mu\text{A}, \ \text{Reference}$ $V_{DS} = 500 \ \text{V}, \ \text{V}_{GS} = 0 \ \text{V}$ $V_{DS} = 400 \ \text{V}, \ \text{T}_{C} = 125 \ \text{T}_{C}$	/, $T_J = 25^{\circ}C$ ed to $25^{\circ}C$ V	500	- 0.6		V
o Source Breakdown Voltage own Voltage Temperature ent ate Voltage Drain Current	$I_D = 250 \ \mu$ A, Reference $V_{DS} = 500 \ V, V_{GS} = 0 \ V$ $V_{DS} = 400 \ V, T_C = 125$	ed to 25°C V	-	0.6	-	
own Voltage Temperature ent ate Voltage Drain Current	$I_D = 250 \ \mu$ A, Reference $V_{DS} = 500 \ V, V_{GS} = 0 \ V$ $V_{DS} = 400 \ V, T_C = 125$	ed to 25°C V	-	0.6	-	
ent ate Voltage Drain Current	$I_D = 250 \ \mu$ A, Reference $V_{DS} = 500 \ V, V_{GS} = 0 \ V$ $V_{DS} = 400 \ V, T_C = 125$	ed to 25°C V			-	V/ºC
ate Voltage Drain Current	$V_{DS} = 500 \text{ V}, \text{ V}_{GS} = 0 \text{ V}$ $V_{DS} = 400 \text{ V}, \text{ T}_{C} = 125 \text{ V}$	V			-	V/-C
· ·	V <sub>DS</sub> = 400 V, T <sub>C</sub> = 125		-	-		
· ·					1	μA
Body Leakage Current				-	10	
	$V_{GS} = \pm 30 \text{ V}, \text{ V}_{DS} = 0 \text{ V}$	V	-	-	±100	nA
s						
nreshold Voltage	V <sub>GS</sub> = V <sub>DS</sub> , I <sub>D</sub> = 250 μ.	A	3.0	-	5.0	V
·	V <sub>GS</sub> = 10 V, I <sub>D</sub> = 2.5 A		-	1.15	1.4	Ω
d Transconductance	V <sub>DS</sub> = 20 V, I <sub>D</sub> = 2.5 A		-	4.3	-	S
eristics						
				400	640	~
•	V <sub>DS</sub> = 25 V, V <sub>GS</sub> = 0 V, f = 1 MHz		-			pF pF
						pF
			-		-	nC
· ·			_		-	nC
	VGS - 10 V	(Note 4)	-	5	-	nC
,	$V_{DD} = 250 \text{ V}, \text{ I}_{D} = 5 \text{ A},$ $V_{GS} = 10 \text{ V}, \text{ R}_{G} = 25 \Omega$		-			ns
			-		-	ns
,				-		ns
		(Note 4)	-	20	50	ns
de Characteristics						
m Continuous Drain to Source D	iode Forward Current		-	-	5	Α
m Pulsed Drain to Source Diode	orward Current		-	-	20	Α
Source Diode Forward Voltage	$V_{GS}$ = 0 V, I <sub>SD</sub> = 5 A		-	-	1.4	V
Recovery Time	V <sub>GS</sub> = 0 V, I <sub>SD</sub> = 5 A,		-	300	-	ns
Recovery Charge	dI <sub>F</sub> /dt = 100 A/µs		-	1.8	-	μC
	m Pulsed Drain to Source Diode Source Diode Forward Voltage Recovery Time Recovery Charge	Drain to Source On Resistance $V_{GS} = 10 \text{ V}, I_D = 2.5 \text{ A}$ d Transconductance $V_{DS} = 20 \text{ V}, I_D = 2.5 \text{ A}$ eristicsapacitance $V_{DS} = 25 \text{ V}, V_{GS} = 0 \text{ V}$ f = 1 MHze Transfer Capacitanceate Charge at 10V $V_{DS} = 400 \text{ V}, I_D = 5 \text{ A},$ Source Gate Charge $V_{GS} = 10 \text{ V}$ Drain "Miller" Chargeteristicsn Delay Timen Rise Timef Delay Timef Fall Timede Characteristicsm Continuous Drain to Source Diode Forward CurrentSource Diode Forward VoltageV_{GS} = 0 V, I_{SD} = 5 A,e Recovery TimeV_{GS} = 0 V, I_{SD} = 5 A,	brain to Source On Resistance $V_{GS} = 10 \text{ V}, I_D = 2.5 \text{ A}$ d Transconductance $V_{DS} = 20 \text{ V}, I_D = 2.5 \text{ A}$ eristicsapacitanceCapacitancee Transfer Capacitanceate Charge at 10VSource Gate ChargeDrain "Miller" Chargeteristicsn Delay Timen Rise Timef Eall Timef Fall Timef Fall Timew Continuous Drain to Source Diode Forward Currentm Pulsed Drain to Source Diode Forward CurrentSource Diode Forward Voltagev_{GS} = 0 V, I_{SD} = 5 A, v_{GS} = 0 V, I_{SD} = 5 A, v_{S} = 0 V, I_{SD} = 5 A, v	brain to Source On Resistance $V_{GS} = 10 \text{ V}, I_D = 2.5 \text{ A}$ -d Transconductance $V_{DS} = 20 \text{ V}, I_D = 2.5 \text{ A}$ -eristicsapacitance $V_{DS} = 25 \text{ V}, V_{GS} = 0 \text{ V}, f = 1 \text{ MHz}$ -capacitance $f = 1 \text{ MHz}$ -e Transfer Capacitance $V_{DS} = 400 \text{ V}, I_D = 5 \text{ A}, V_{GS} = 10 \text{ V}$ -source Gate Charge $V_{DS} = 400 \text{ V}, I_D = 5 \text{ A}, V_{GS} = 10 \text{ V}$ -Drain "Miller" Charge $V_{DD} = 250 \text{ V}, I_D = 5 \text{ A}, V_{GS} = 10 \text{ V}$ -teristicsn Delay Time $V_{DD} = 250 \text{ V}, I_D = 5 \text{ A}, V_{GS} = 10 \text{ V}, R_G = 25 \Omega$ -f Delay Time $V_{DS} = 10 \text{ V}, R_G = 25 \Omega$ -f Fall Time $V_{OS} = 0 \text{ V}, I_S = 5 \text{ A}, V_{GS} = 0 \text{ V}, I_S = 0 $	brain to Source On Resistance $V_{GS} = 10 \text{ V}, I_D = 2.5 \text{ A}$ -1.15d Transconductance $V_{DS} = 20 \text{ V}, I_D = 2.5 \text{ A}$ -4.3eristics-4.3apacitance $V_{DS} = 20 \text{ V}, I_D = 2.5 \text{ A}$ -4.3capacitance $V_{DS} = 20 \text{ V}, V_{GS} = 0 \text{ V}, f = 1 \text{ MHz}$ -480capacitancef = 1 \text{ MHz}-66e Transfer Capacitance-5ate Charge at 10V $V_{DS} = 400 \text{ V}, I_D = 5 \text{ A}, V_{GS} = 10 \text{ V}$ -Source Gate Charge $V_{CS} = 10 \text{ V}$ -3Drain "Miller" Charge-13n Rise Time $V_{DD} = 250 \text{ V}, I_D = 5 \text{ A}, V_{GS} = 10 \text{ V}, R_G = 25 \Omega$ -teristics-13n Rise Time $V_{CS} = 10 \text{ V}, R_G = 25 \Omega$ -f Delay Time-20d Characteristicsm Continuous Drain to Source Diode Forward Currentm Pulsed Drain to Source Diode Forward Currentsource Diode Forward Voltage $V_{GS} = 0 \text{ V}, I_{SD} = 5 \text{ A},e Recovery TimeV_{GS} = 0 \text{ V}, I_{SD} = 5 \text{ A},e Recovery ChargedIF/dt = 100 A/\mus-1.8$	$\begin{array}{c c c c c c c c c c c c c c c c c c c $

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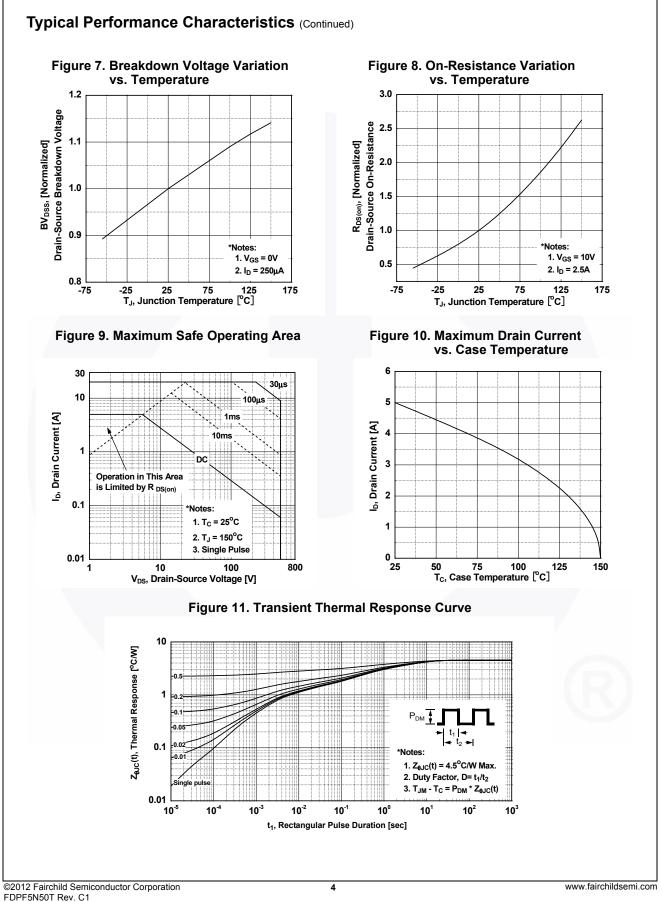
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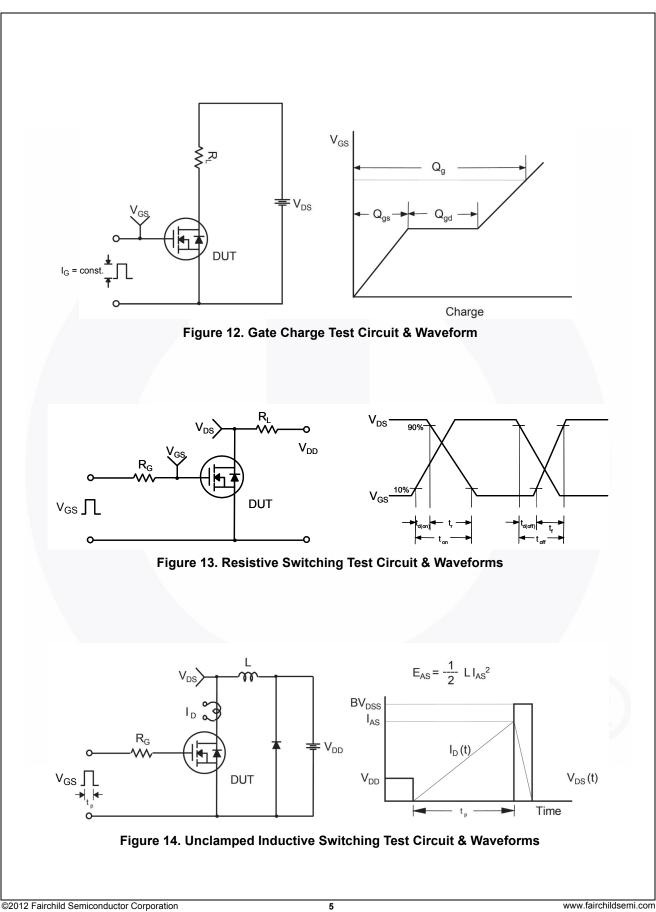
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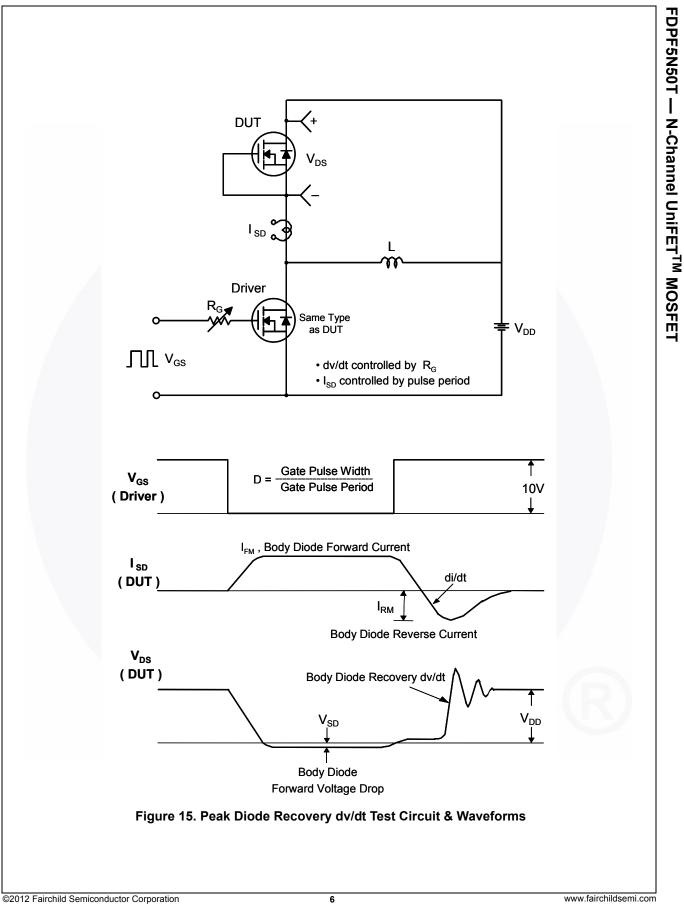




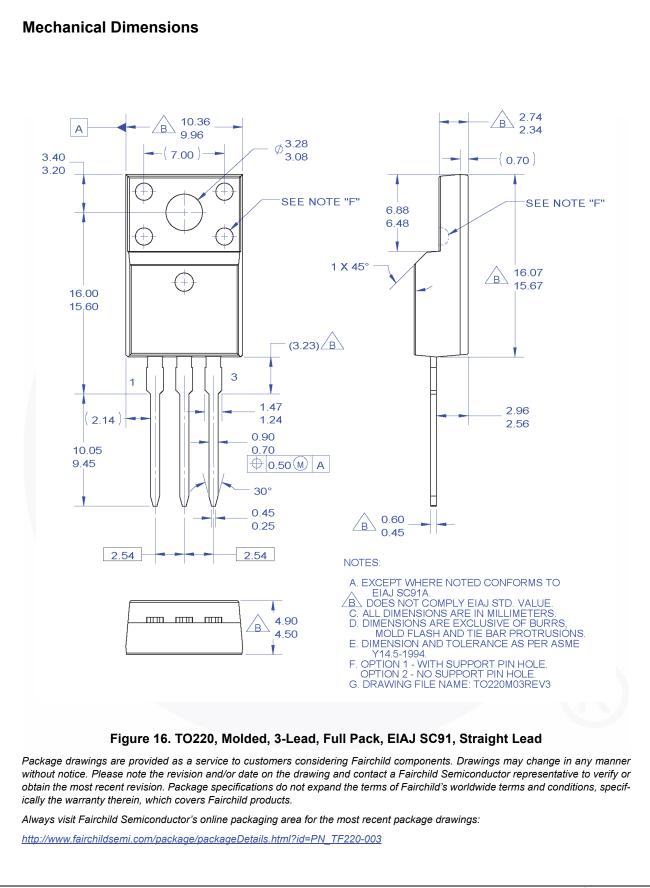


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